Application/Control No. Applicant(s)/Patent Under Reexamination 10/743,441 KAWAUCHI ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Sin J. Lee 1752 **U.S. PATENT DOCUMENTS** Date Document Number Name Classification Country Code-Number-Kind Code MM-YYYY US-2003/0165775 A1 09-2003 Endo et al. Α 430/278.1 В US-US-С D US-US-Е US-F US-G US-Н US-US-US-K US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code-MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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